

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of : Customer Number: 20277  
: Confirmation Number:  
Shinya TOKUNAGA, et al. :  
: Group Art Unit:  
Serial No.:  
: Examiner:  
Filed: November 26, 2003 :  
:  
For: MASK PATTERN INSPECTING METHOD, INSPECTION APPARATUS,  
INSPECTING DATA USED THEREIN AND INSPECTING DATA GENERATING  
METHOD

**INFORMATION DISCLOSURE STATEMENT**

Mail Stop Patent Application  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

**Serial No.:**

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION  (PTO-1449)			ATTY. DOCKET NO. <b>61282-048</b>		SERIAL NO.		
			APPLICANT <b>Shinya TOKUNAGA, et al.</b>				
			FILING DATE <b>November 26, 2003</b>		GROUP		
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sub>2</sub> ( <i>if known</i> )	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document			
	US						
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<b>FOREIGN PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number +-Kind Codes ( <i>if known</i> )	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
		JP 2000-113189 (w/ English Abstract)	04/21/2000	TOSHIBA CORP.			
		JP 2002-196483 (w/ English Abstract)	07/12/2002	HITACHI LTD.			
		JP 2003-121983 (w/ English Abstract)	04/23/2003	DAINIPPON PRINTING CO., LTD.			
		JP 2002-258463 (w/ English Abstract)	09/11/2002	DAINIPPON PRINTING CO., LTD.			
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
EXAMINER			DATE CONSIDERED				

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Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.